

AMENDMENTS TO THE SPECIFICATION:

Please replace paragraph [0010] with the following rewritten paragraph:

- 1 **[0010]** In the preferred embodiment, the Built In Self Test method, for measuring
2 jitter tolerance and jitter transfer on transceivers, makes use of transmit (TX) side
3 interpolator to generate desired jitter test patterns. The TX serial data thus
4 generated is looped back to the receive (RX) serial input. Pseudo Random
5 Binary Sequence (PRBS) PRBS generation/verification mechanism is used to
6 check jitter tolerance and a special up/down counter is used to monitor the
7 movement of the RX clock recovery system and thus measure jitter transfer.

Please replace paragraph [0012] with the following rewritten paragraph:

- 1 **[0012]** Aspects of the present invention provide a Built-In Self-Test (BIST) ~~BIST~~
2 that can be performed on every device shipped and test for jitter tolerance and
3 transfer. This test can be implemented simply by utilizing the PRBS checking
4 mechanism that exists on present day devices. In some embodiments, an
5 up/down counter is used to monitor activity of the receive clock recovery
6 mechanism and test for jitter transfer.